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PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: BRUEGEMANN, Lutz et al. ) Examiner:  
Application No.: 10/810,819 ) unknown  
Filing Date: March 29, 2004 ) Art Unit:  
For: X-RAY OPTICAL SYSTEM FOR ) unknown  
COMBINATORIAL SCREENING OF A )  
SAMPLE LIBRARY )

Atty. Docket No.: P8183US

Commissioner for Patents  
Alexandria, VA 22313-1450  
U.S.A.

TRANSMITTAL LETTER FOR INFORMATION DISCLOSURE STATEMENT

Please find enclosed:

1. an Information Disclosure Statement under 37 CFR 1.97 (b)(3).
2. Return Postcard

Please charge my Deposit Account No. 11-1447 in the amount of US \$ to cover the above fees.

( ) A check in the amount of US \$ is enclosed.

( ) Applicant believes that this submission is timely and that no petition for an extension of time under 37 CFR 1.136(a) is required.

( ) Applicant, however, conditionally petitions for such an extension should same be necessary.

(X) The Commissioner is hereby authorized to charge any additional fees which may be required, or credit any overpayment to Deposit Account No. 11-1447.

Respectfully submitted,

Paul Vincent

Dr. Paul Vincent,  
Reg. No. 37,461

July 28, 2005

Date

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**INFORMATION DISCLOSURE STATEMENT**

The undersigned herewith requests the Examiner to consider the art listed in the attached Disclosure Statement (PTO 1449) in examination of the above referenced U.S. patent application.

This submittal is being made under 37 CFR 1.97 (b)(3). No fee is due. If any fees are necessary, please charge same to Account No. 11-1447.

Respectfully submitted,

Paul Vincent

Dr. Paul Vincent  
Reg. No. 37,461

Tly 28, 2005  
Date

Enclosures:

PTO-Form 1449 (2 pages)

European Search Report and translation of relevant portions thereof  
Copies of cited references which are not US patents or publications

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Substitute for form 1449A/PTO				<u>Complete if Known</u>	
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b> (Use as many sheets as necessary)				<b>Application Number</b> <u>10/810,819</u> <b>Filing Date</b> <u>March 29, 2004</u> <b>First Named Inventor</b> <u>BRUEGEMANN, Lutz</u> <b>Group Art Unit</b> <b>Examiner Name</b>	
<b>Sheet</b>	<b>1</b>	<b>of</b>	<b>2</b>	<b>Attorney Docket Number</b>	<b>P8183US</b>

**U. S. PATENT DOCUMENTS**

## FOREIGN PATENT DOCUMENTS

<b>Examiner Signature</b>		<b>Date Considered</b>	
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Substitute for form 1449B/PTO				<b>Complete if Known</b>	
				Application Number	10/810,819
				Filing Date	March 29, 2003
				First Named Inventor	BRUEGEMANN, Lutz
				Group Art Unit	
				Examiner Name	
Sheet	2	of	2	Attorney Docket Number	P8183US

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS					
Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s). publisher, city and/or country where published			T
		<p>OMOTE K et al.            "A convergent beam parallel detection X-ray diffraction system for characterizing combinatorial epitaxial thin films"            Combinatorial and Composition Spread Techniques in Materials and Device Development, San Jose, CA, USA, 01.26.2000, Bd. 3941, Pages 84-91, XP002291973            Proceedings of the SPIE - The International Society for Optical Engineering, 2000, SPIE-Int. Soc. Opt. Eng, USA            ISSN: 0277-786X, Fig. 1</p>			
		<p>ISAACS E D ET AL.;            "Synchrotron X-Ray Microbeam Diagnostics of Combinatorial Synthesis".            Applied Physics Letters, American Institute of Physics.            New York, US., Vol. 73, Nr. 13,            Pages 1820 - 1822, XP001120660, ISSN: 003-6951,            Page 1820, last Par. - Page 1821, Par. 1, Fig. 1</p>			

Examiner Signature		Date Considered	
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